09/844,675

L Number	Hits	Search Text	DB	Time stamp
-	3664260	signal generator\$1 and (test signal\$1 with (CUT or DUT or DFT or	USPAT;	2004/01/17 16:37
		SUT))	US-PGPUB;	
		•	EPO; JPO;	
			DERWENT;	
			IBM_TDB	
_	3632519	signal digitizer\$1 and ((extract\$3 near1 digital signal\$1) with (test	USPAT;	2004/01/17 16:40
-	3032319	and measurement) with (CUTor DUT or SUT or DFT))	US-PGPUB;	2001/01/17 10.40
		and measurement, with (corol bot of 501 of birty)	EPO; JPO;	
			DERWENT;	
			IBM_TDB	
		(signal consents and (test signals) with (CUT or DUT or DUT	USPAT	2004/01/17 16:42
-	993807	(signal generator\$1 and (test signal\$1 with (CUT or DUT or DFT or	USPAT	2004/01/17 16:43
		SUT))) and (signal digitizer\$1 and ((extract\$3 near1 digital		
		signal\$1) with (test and measurement) with (CUTor DUT or SUT		
		or DFT)))		
-	434730	integrated excitation/extraction system\$1 with (test and	USPAT	2004/01/17 16:43
		measurement with CUT near2 chip\$1)		
-	273024	((signal generator\$1 and (test signal\$1 with (CUT or DUT or DFT	USPAT	2004/01/17 16:46
		or SUT))) and (signal digitizer\$1 and ((extract\$3 near1 digital		
		signal\$1) with (test and measurement) with (CUTor DUT or SUT		
		or DFT)))) and (integrated excitation/extraction system\$1 with		
		(test and measurement with CUT near2 chip\$1))		
-	694462	analog reconstruction filter\$1	USPAT	2004/01/17 16:46
-	877328	generat\$3 and (filtered test signal\$1)	USPAT	2004/01/17 16:47
-	391189	(analog reconstruction filter\$1) and (generat\$3 and (filtered test	USPAT	2004/01/17 16:47
		signal\$1))		
-	994853	signal digitizer\$1	USPAT	2004/01/17 16:48
-	330623	((analog reconstruction filter\$1) and (generat\$3 and (filtered test	USPAT	2004/01/17 16:48
	330023	signal\$1))) and (signal digitizer\$1)	00.7	2001/02/27 20110
_	609494	sequential shift register\$1	USPAT	2004/01/17 16:49
_	158551	(((analog reconstruction filter\$1) and (generat\$3 and (filtered test	USPAT	2004/01/17 16:49
	130331	signal\$1))) and (signal digitizer\$1)) and (sequential shift	USFAI	2004/01/17 10.49
		register\$1)		
	62848		USPAT	2004/01/17 16:50
-	02040	(((signal generator\$1 and (test signal\$1 with (CUT or DUT or DFT	USPAT	2004/01/17 16:50
		or SUT))) and (signal digitizer\$1 and ((extract\$3 near1 digital		
		signal\$1) with (test and measurement) with (CUTor DUT or SUT		
		or DFT)))) and (integrated excitation/extraction system\$1 with		
		(test and measurement with CUT near2 chip\$1))) and ((((analog		
		reconstruction filter\$1) and (generat\$3 and (filtered test		
		signal\$1))) and (signal digitizer\$1)) and (sequential shift		
		register\$1))	l 	
-	2412567	reference voltage generator\$1	USPAT	2004/01/17 16:50
-	2555541	variable DC reference voltage signal\$1	USPAT	2004/01/17 16:51
-	2385085	(reference voltage generator\$1) with (variable DC reference	USPAT	2004/01/17 16:52
		voltage signal\$1)		
-	61684	((((signal generator\$1 and (test signal\$1 with (CUT or DUT or DFT	USPAT	2004/01/17 16:53
		or SUT))) and (signal digitizer\$1 and ((extract\$3 near1 digital		
		signal\$1) with (test and measurement) with (CUTor DUT or SUT		
		or DFT)))) and (integrated excitation/extraction system\$1 with		
		(test and measurement with CUT near2 chip\$1))) and ((((analog		
		reconstruction filter\$1) and (generat\$3 and (filtered test		
		signal\$1))) and (signal digitizer\$1)) and (sequential shift		
		register\$1))) and ((reference voltage generator\$1) with (variable		
		DC reference voltage signal\$1))		
-	122493	comparator\$1 and (response signal\$! with reference voltage\$1)	USPAT	2004/01/17 16:53
_	161318	extract\$3 and (digital signal\$1)	USPAT	2004/01/17 16:54
_	19051	(comparator\$1 and (response signal\$! with reference voltage\$1))	USPAT	2004/01/17 16:54
	170JI	and (extract\$3 and (digital signal\$1))	331711	200 02/1/ 10.57

-	4636	(((((signal generator\$1 and (test signal\$1 with (CUT or DUT or DFT or SUT))) and (signal digitizer\$1 and ((extract\$3 near1 digital	USPAT	2004/01/17 16:55
				:
		signal\$1) with (test and measurement) with (CUTor DUT or SUT		
		or DFT)))) and (integrated excitation/extraction system\$1 with		
		(test and measurement with CUT near2 chip\$1))) and ((((analog		
		reconstruction filter\$1) and (generat\$3 and (filtered test		
		signal\$1))) and (signal digitizer\$1)) and (sequential shift		
		register\$1))) and ((reference voltage generator\$1) with (variable		
		DC reference voltage signal\$1))) and ((comparator\$1 and		1
		(response signal\$! with reference voltage\$1)) and (extract\$3 and		
	2205	(digital signal\$1)))	LICOAT	2004/01/17 16:50
-	3205	714/718.ccls. or 714/740.ccls. or 714/738.ccls. or 714/736.ccls. or	USPAT	2004/01/17 16:58
ĺ		714/725.ccls. or 714/724.ccls. or 714/721.ccls. or 714/799.ccls. or		
	20	324/?.ccls.	LICOAT	2004/01/47 46:50
-	29	((((((signal generator\$1 and (test signal\$1 with (CUT or DUT or	USPAT	2004/01/17 16:59
		DFT or SUT))) and (signal digitizer\$1 and ((extract\$3 near1 digital		
		signal\$1) with (test and measurement) with (CUTor DUT or SUT	[
		or DFT)))) and (integrated excitation/extraction system\$1 with		
		(test and measurement with CUT near2 chip\$1))) and ((((analog		
		reconstruction filter\$1) and (generat\$3 and (filtered test		
		signal\$1))) and (signal digitizer\$1)) and (sequential shift		
		register\$1))) and ((reference voltage generator\$1) with (variable DC reference voltage signal\$1))) and ((comparator\$1 and		
	:	(response signal\$! with reference voltage\$1)) and (extract\$3 and		
		(digital signal\$1)))) and (714/718.ccls. or 714/740.ccls. or		
		714/738.ccls. or 714/736.ccls. or 714/725.ccls. or 714/724.ccls. or		
		714/736.ccis. or 714/736.ccis. or 714/723.ccis. or 714/724.ccis. or 714/721.ccis. or 324/?.ccis.)		
	761319	memory circuit\$1 with sequential shift register\$1	USPAT	2004/01/17 16:59
	1084012	signal generator\$1	USPAT	2004/01/17 17:00
_	260010	signal generator\$1 (signal generator\$1) with (memory circuit\$1 with sequential shift	USPAT	2004/01/17 17:00
-	:	register\$1)		
-	25	((signal generator\$1) with (memory circuit\$1 with sequential shift	USPAT	2004/01/17 17:01
		register\$1)) and ((((((signal generator\$1 and (test signal\$1 with		
		(CUT or DUT or DFT or SUT))) and (signal digitizer\$1 and		
		((extract\$3 near1 digital signal\$1) with (test and measurement)		
		with (CUTor DUT or SUT or DFT)))) and (integrated		
		excitation/extraction system\$1 with (test and measurement with	i	
		CUT near2 chip\$1))) and ((((analog reconstruction filter\$1) and (generat\$3 and (filtered test signal\$1))) and (signal digitizer\$1))		
		and (sequential shift register\$1))) and ((reference voltage		
		generator\$1) with (variable DC reference voltage signal\$1))) and		
		((comparator\$1 and (response signal\$! with reference voltage\$1))		
		and (extract\$3 and (digital signal\$1)))) and (714/718.ccls. or		
		714/740.ccls. or 714/738.ccls. or 714/736.ccls. or 714/725.ccls. or		
		714/724.ccls. or 714/736.ccls. or 714/799.ccls. or 324/?.ccls.))		
_	1394636	pulse density modulation signal\$1	USPAT	2004/01/17 17:01
_	1183716	program\$4 with reference voltage signal\$1	USPAT	2004/01/17 17:02
_	566545	averaging circuit\$1 with passive RC filter\$1	USPAT .	2004/01/17 17:03
_	336750	(program\$4 with reference voltage signal\$1) and (averaging	USPAT	2004/01/17 17:03
	330,30	circuit\$1 with passive RC filter\$1)	331711	250 1,01,17 17:05
	322985	(pulse density modulation signal\$1) and ((program\$4 with	USPAT	2004/01/17 17:04
	322303	reference voltage signal\$1) and (averaging circuit\$1 with passive		
		RC filter\$1))		
_	1070706	periodic signal\$1	USPAT	2004/01/17 17:05
-	309641	(periodic signal\$1) and ((pulse density modulation signal\$1) and	USPAT	2004/01/17 17:06
	3333.1	((program\$4 with reference voltage signal\$1) and (averaging] 33.7.1	
		circuit\$1 with passive RC filter\$1)))		
	I	underta viter passive the interpa///	1	·

-	1488645 7	(((signal generator\$1) with (memory circuit\$1 with sequential shift register\$1)) and (((((((signal generator\$1 and (test signal\$1 with (CUT or DUT or DFT or SUT))) and (signal digitizer\$1 and ((extract\$3 near1 digital signal\$1) with (test and measurement) with (CUTor DUT or SUT or DFT)))) and (integrated excitation/extraction system\$1 with (test and measurement with CUT near2 chip\$1))) and ((((analog reconstruction filter\$1) and (generat\$3 and (filtered test signal\$1))) and (signal digitizer\$1)) and (sequential shift register\$1))) and ((reference voltage generator\$1) with (variable DC reference voltage signal\$1))) and ((comparator\$1 and (response signal\$! with reference voltage\$1)) and (extract\$3 and (digital signal\$1)))) and (714/718.ccls. or 714/740.ccls. or 714/738.ccls. or 714/736.ccls. or 714/725.ccls. or 714/724.ccls. or 714/721.ccls. or 714/799.ccls. or 324/?.ccls.))) and ((periodic signal\$1) and ((pulse density modulation signal\$1) and ((program\$4 with reference voltage signal\$1) and (averaging circuit\$1 with passive RC filter\$1)))) single scan-chain integrated near2 chip\$1 ((((signal generator\$1) with (memory circuit\$1 with sequential	USPAT USPAT USPAT	2004/01/17 17:08 2004/01/17 17:08 2004/01/17 17:09
		shift register\$1)) and (((((((signal generator\$1 and (test signal\$1 with (CUT or DUT or DFT or SUT))) and (signal digitizer\$1 and ((extract\$3 near1 digital signal\$1) with (test and measurement) with (CUTor DUT or SUT or DFT)))) and (integrated excitation/extraction system\$1 with (test and measurement with CUT near2 chip\$1))) and ((((analog reconstruction filter\$1) and (generat\$3 and (filtered test signal\$1))) and (signal digitizer\$1)) and (sequential shift register\$1))) and ((reference voltage generator\$1) with (variable DC reference voltage signal\$1))) and ((comparator\$1 and (response signal\$! with reference voltage\$1)) and (extract\$3 and (digital signal\$1)))) and (714/718.ccls. or 714/740.ccls. or 714/738.ccls. or 714/736.ccls. or 714/725.ccls. or 714/724.ccls. or 714/721.ccls. or 714/799.ccls. or 324/?.ccls.))) and ((periodic signal\$1) and ((pulse density modulation signal\$1) and ((program\$4 with reference voltage signal\$1) and (averaging circuit\$1 with passive RC filter\$1))))) and (single scan-chain integrated near2 chip\$1)		
-	995254 13507 7	programming near1 signal generator\$1 with test signal\$1 passively filtering with periodic bit-stream\$1 ((((signal generator\$1) with (memory circuit\$1 with sequential shift register\$1)) and ((((((signal generator\$1 and (test signal\$1 with (CUT or DUT or DFT or SUT))) and (signal digitizer\$1 and ((extract\$3 near1 digital signal\$1) with (test and measurement) with (CUTor DUT or SUT or DFT))) and (integrated excitation/extraction system\$1 with (test and measurement with CUT near2 chip\$1))) and ((((analog reconstruction filter\$1) and (generat\$3 and (filtered test signal\$1))) and (signal digitizer\$1)) and (sequential shift register\$1))) and ((reference voltage generator\$1) with (variable DC reference voltage signal\$1))) and ((comparator\$1 and (response signal\$1)))) and (714/718.ccls. or 714/740.ccls. or 714/738.ccls. or 714/736.ccls. or 714/725.ccls. or 714/724.ccls. or 714/721.ccls. or 714/799.ccls. or 324/?.ccls.))) and ((periodic signal\$1) and ((pulse density modulation signal\$1) and ((program\$4 with reference voltage signal\$1) and (averaging circuit\$1 with passive RC filter\$1)))) and (single scan-chain integrated near2 chip\$1)) and (programming near1 signal generator\$1 with test signal\$1)	USPAT USPAT USPAT	2004/01/17 17:10 2004/01/17 17:11 2004/01/17 17:11
-	1389024	generator\$1 with test signal\$1) channel encoder\$1 and (channel encoding input information bit\$1 with outputting encoded symbol\$1)	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2004/01/19 14:00